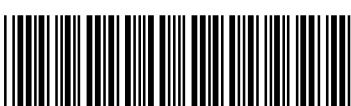


Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10560517	ALI-HACKL ET AL.
	Examiner HUY D NGUYEN	Art Unit 2617

SEARCHED

Class	Subclass	Date	Examiner
370	350, 318	10/23/2008	HN
455	13.4, 522, 127.1	10/23/2008	HN
Updated search	same as above	4/27/2009	HN
Updated search	same as above	11/25/2009	HN
Updated search	same as above	5/18/2010	HN

SEARCH NOTES

Search Notes	Date	Examiner
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	10/23/2008	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	4/27/2009	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	11/25/2009	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT, IBM_TDB). See search history.	5/18/2010	HN
See interference search.	5/18/2010	HN

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
370	350, 318	5/18/2010	HN
455	13.4, 522, 127.1	11/25/2009	HN

--	--